

P50 FR N66_DFT-QPSK45M_Rear Face_1.5cm_Ch346500_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band n66	5G NR FR1 FDD, -	1732.500, 346500	8.31	1.40	39.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1750-2025-02-20	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

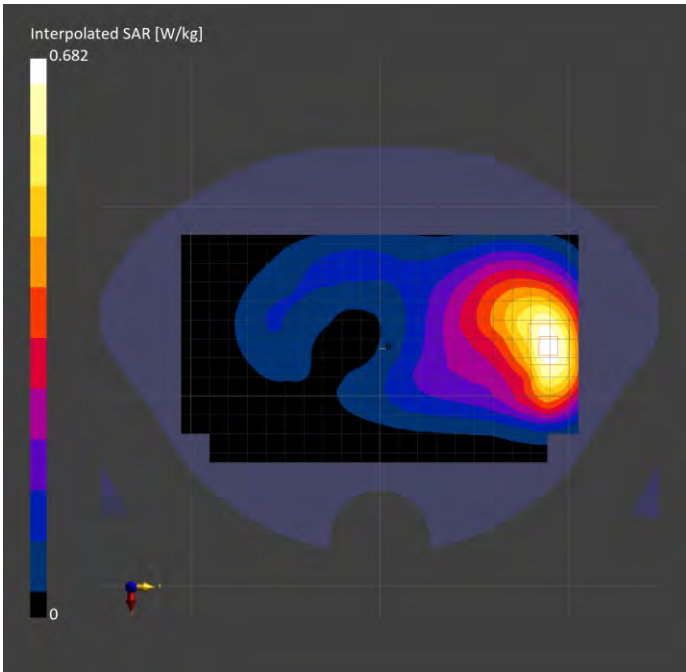
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-20	2025-02-20
psSAR1g [W/kg]	0.565	0.569
psSAR10g [W/kg]	0.344	0.359
Power Drift [dB]	-0.01	-0.12
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.3
Dist 3dB Peak [mm]		16.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P51 FR N77_DFT-QPSK100M_Rear Face_Ch633334_135RB_OS69

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 10.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band n77	5G NR FR1 TDD, -	3500.010, 633334	6.71	2.79	39.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL3500_2025-03-06	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

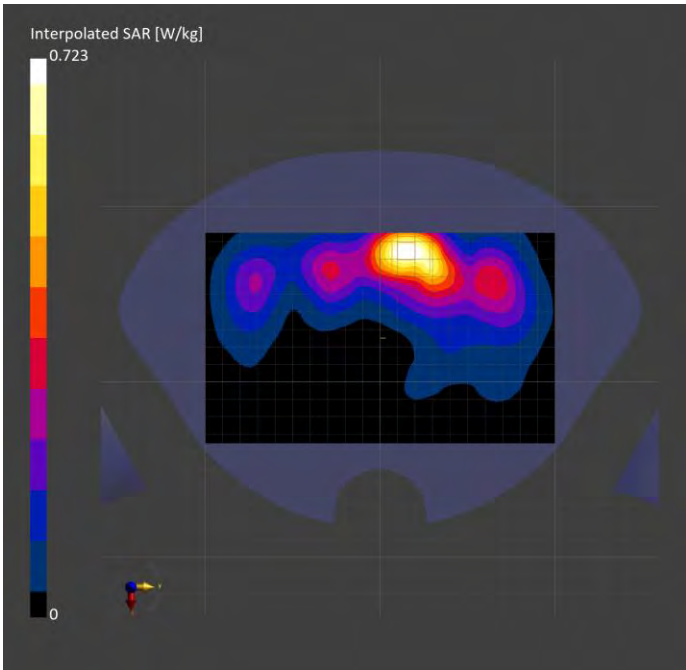
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-06	2025-03-06
psSAR1g [W/kg]	0.593	0.600
psSAR10g [W/kg]	0.266	0.285
Power Drift [dB]	-0.09	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.4
Dist 3dB Peak [mm]		14.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P52 FR N78_DFT-QPSK100M_Rear Face_1.5cm_Ch633334_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 10.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band n78	5G NR FR1 TDD, -	3500.010, 633334	6.71	2.83	39.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL3500-2025-03-09	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

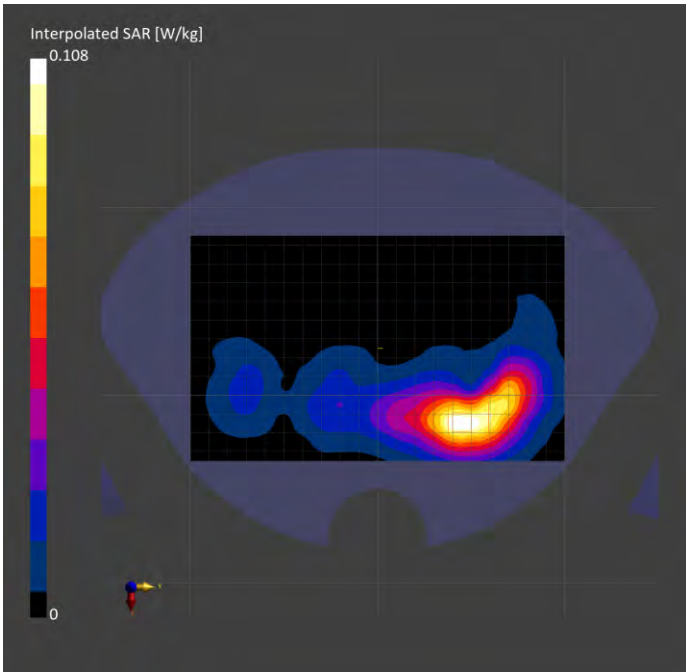
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 2.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-09	2025-03-09
psSAR1g [W/kg]	0.081	0.081
psSAR10g [W/kg]	0.038	0.036
Power Drift [dB]	0.01	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		70.6
Dist 3dB Peak [mm]		11.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P53 WLAN2.4G_802.11ax HE20_Rear Face_1.5cm_Ch1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 10.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	WLAN 2.4GHz	WLAN, -	2412.000, 1	7.46	1.70	40.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-02-27	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

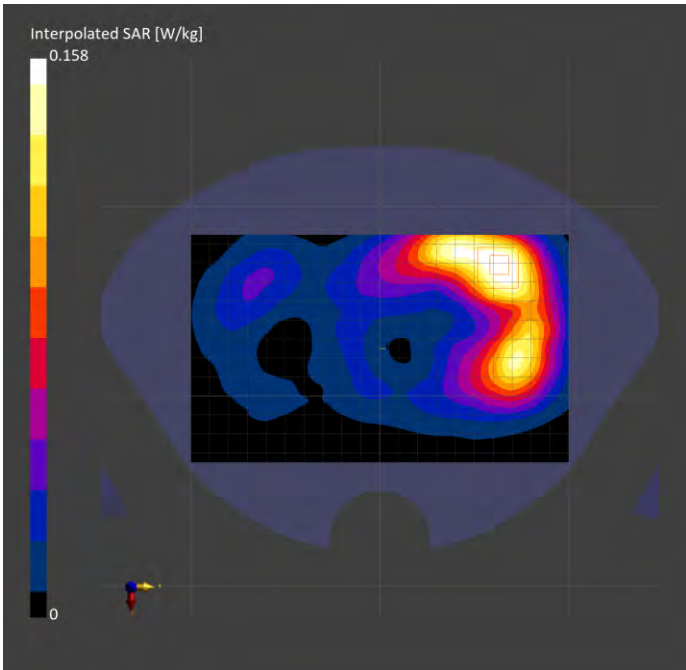
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-27	2025-02-27
psSAR1g [W/kg]	0.129	0.131
psSAR10g [W/kg]	0.074	0.073
Power Drift [dB]	-0.06	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		53.6
Dist 3dB Peak [mm]		13.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P54 WLAN5.2G_802.11n HT20_Rear Face_1.5cm_Ch40

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	WLAN 5GHz	WLAN, -	5200.000, 40	5.16	4.52	35.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL5G-2025-03-11	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

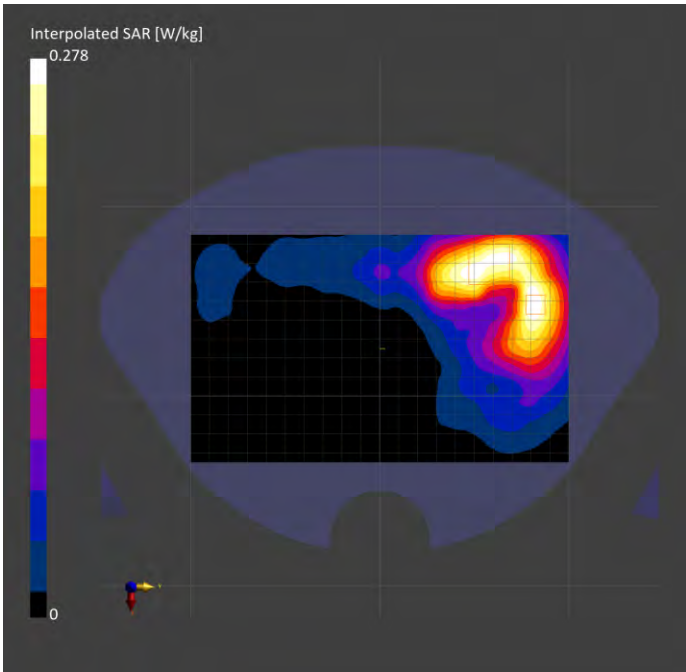
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 2.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-11	2025-03-11
psSAR1g [W/kg]	0.205	0.192
psSAR10g [W/kg]	0.089	0.078
Power Drift [dB]	0.08	-0.13
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		56.5
Dist 3dB Peak [mm]		9.7

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P55 WLAN5.2G_802.11ax HE20_Rear Face_1.5cm_Ch64

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	WLAN 5GHz	WLAN, -	5320.000, 64	5.16	4.75	35.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL5G-2025-03-11	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

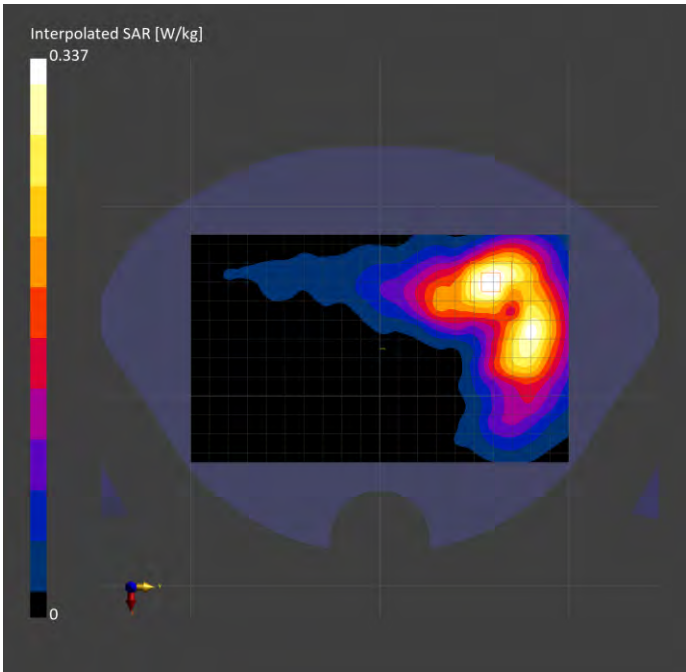
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-11	2025-03-11
psSAR1g [W/kg]	0.257	0.276
psSAR10g [W/kg]	0.109	0.114
Power Drift [dB]	-0.17	-0.13
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		62.6
Dist 3dB Peak [mm]		13.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P56 WLAN5.5G_802.11n HT20_Rear Face_1.5cm_Ch140

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 10.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	WLAN 5GHz	WLAN, -	5700.000, 140	5.16	5.06	35.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-03-12	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

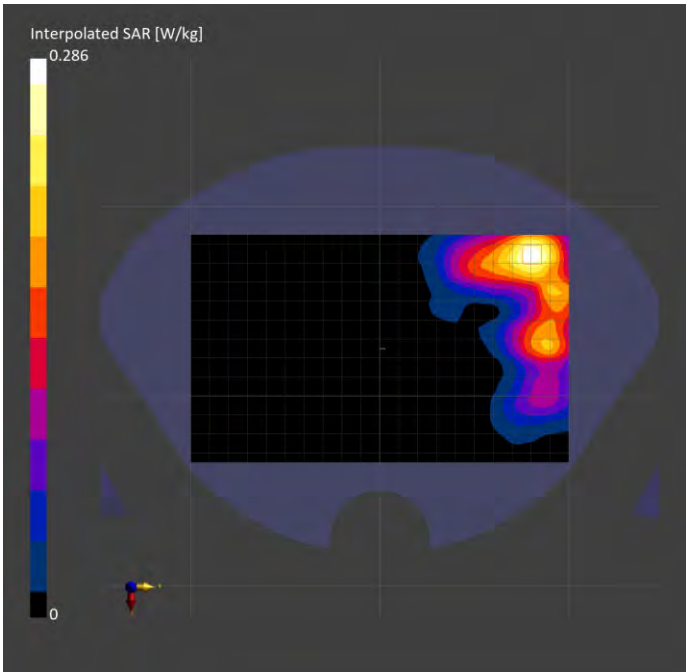
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-12	2025-03-12
psSAR1g [W/kg]	0.209	0.209
psSAR10g [W/kg]	0.085	0.082
Power Drift [dB]	-0.05	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		63.5
Dist 3dB Peak [mm]		17.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P57 WLAN5.8G_802.11be HE20_Rear Face_1.5cm_Ch157

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 10.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	WLAN 5GHz	WLAN, -	5785.000, 157	5.16	5.13	35.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-03-13	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

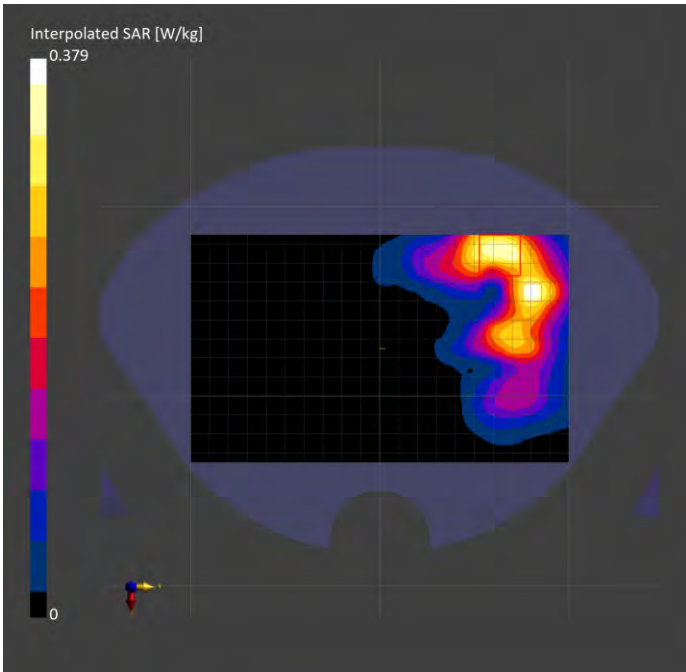
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 2.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-13	2025-03-13
psSAR1g [W/kg]	0.272	0.235
psSAR10g [W/kg]	0.107	0.094
Power Drift [dB]	-0.03	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		51.6
Dist 3dB Peak [mm]		11.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P58 BT_GFSK_Front Face_1.5cm_Ch0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	FRONT, 15.00	ISM 2.4 GHz Band	Bluetooth, -	2402.000, 0	7.46	1.72	40.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-02-27	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

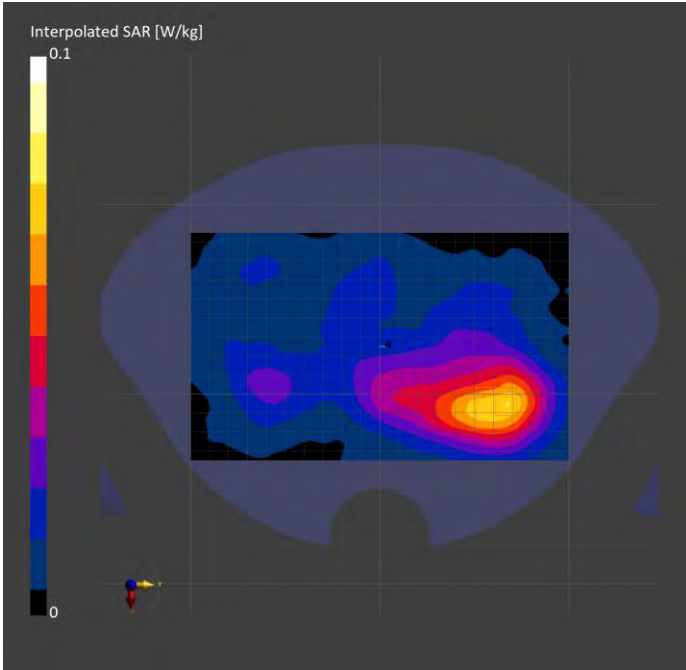
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-27	2025-02-27
psSAR1g [W/kg]	0.060	0.060
psSAR10g [W/kg]	0.034	0.036
Power Drift [dB]	0.04	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.5
Dist 3dB Peak [mm]		17.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P59 GSM850_GPRS 3Tx Slot_Left Side_1cm_Ch189_Ant1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE LEFT, 10.00	GSM 850	GSM, -	836.400, 189	9.47	0.920	43.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL835-2025-02-16	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

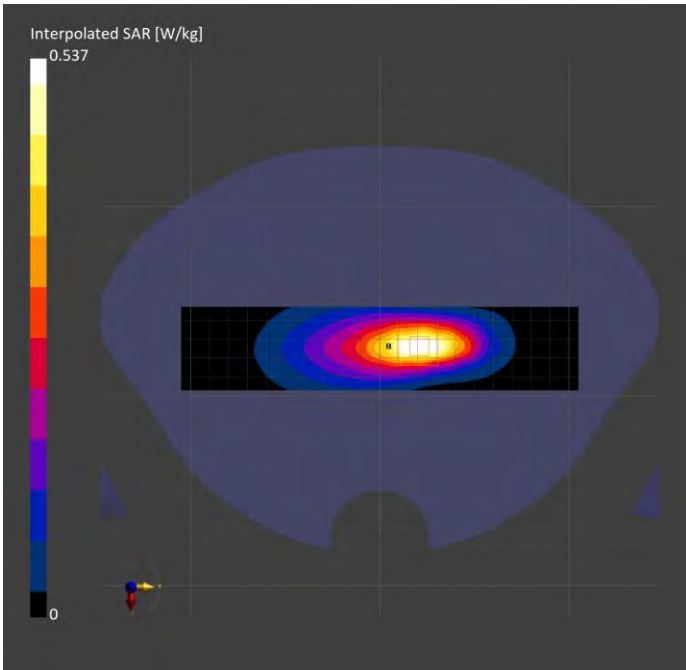
	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-16	2025-02-16
psSAR1g [W/kg]	0.456	0.473
psSAR10g [W/kg]	0.268	0.260
Power Drift [dB]	-0.01	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		75.6
Dist 3dB Peak [mm]		8.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P60 GSM1900_GPRS 2Tx Slot_Top Side_1cm_Ch661

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 10.00	PCS 1900	GSM, -	1880.000, 661	7.97	1.38	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1950-2025-02-26	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

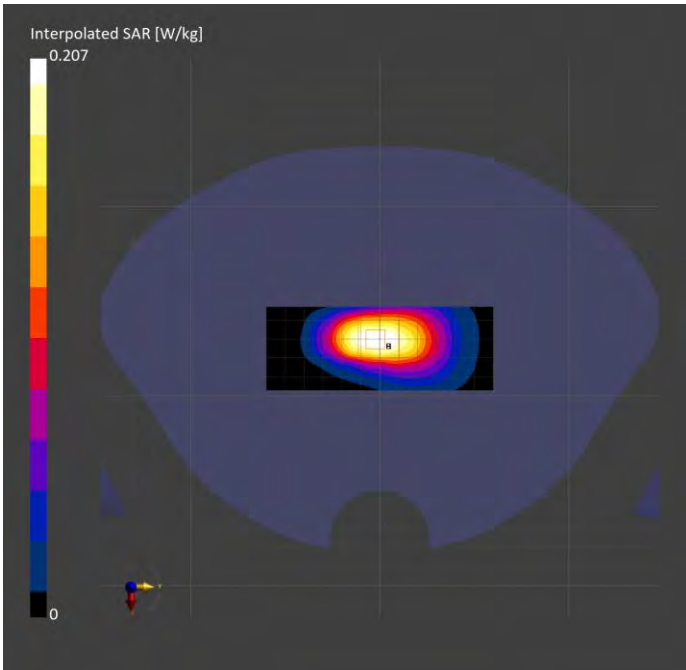
	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-26	2025-02-26
psSAR1g [W/kg]	0.172	0.186
psSAR10g [W/kg]	0.098	0.102
Power Drift [dB]	-0.04	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.9
Dist 3dB Peak [mm]		10.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P61 WCDMA II_RMC12.2K_Top Side_1cm_Ch9262

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 10.00	Band 2	WCDMA, -	1852.400, 9262	7.97	1.36	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1950-2025-02-26	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

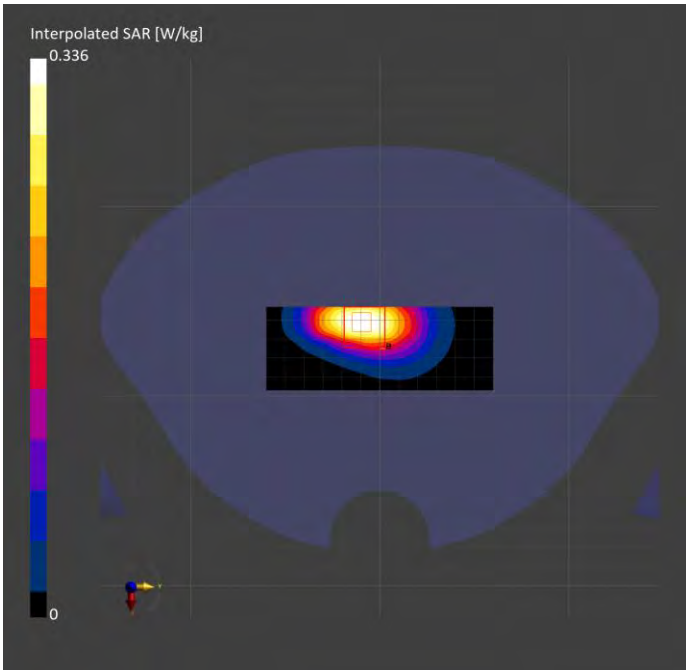
	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-26	2025-02-26
psSAR1g [W/kg]	0.276	0.289
psSAR10g [W/kg]	0.148	0.162
Power Drift [dB]	0.02	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.9
Dist 3dB Peak [mm]		11.9

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P62 WCDMA IV_RMC12.2K_Bottom Side_1cm_Ch1513

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 4	WCDMA, -	1752.600, 1513	8.31	1.34	41.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1750-2025-02-17	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

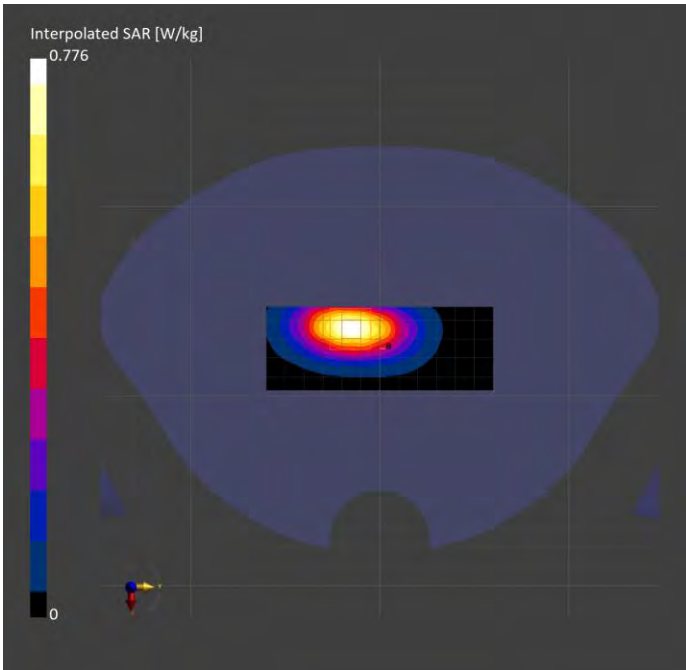
	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-17	2025-02-17
psSAR1g [W/kg]	0.615	0.642
psSAR10g [W/kg]	0.331	0.347
Power Drift [dB]	-0.01	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.1
Dist 3dB Peak [mm]		9.7

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P63 WCDMA V_RMC12.2K_Right Side_1cm_Ch4182

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE RIGHT, 10.00	Band 5	WCDMA, -	836,400, 4182	9.47	0.942	43.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL835-2025-02-18	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

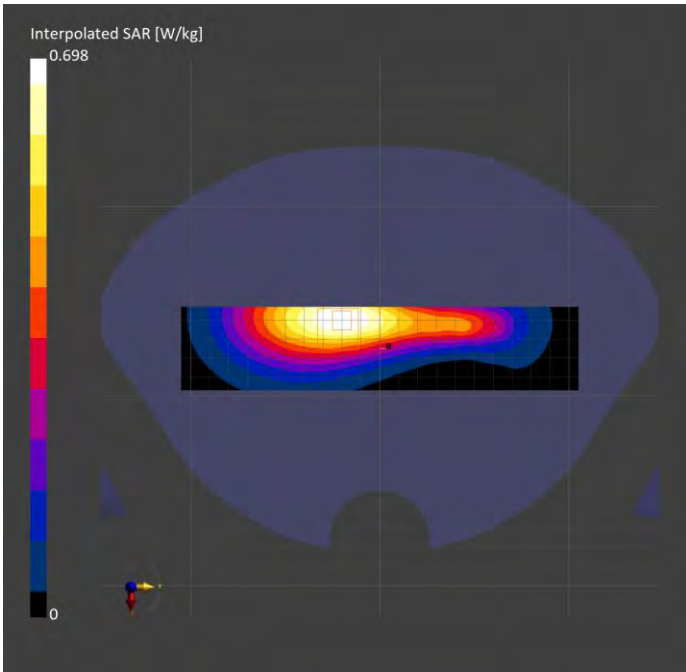
	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-18	2025-02-18
psSAR1g [W/kg]	0.604	0.654
psSAR10g [W/kg]	0.381	0.422
Power Drift [dB]	-0.02	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.2
Dist 3dB Peak [mm]		15.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P64 LTE B2_QPSK20M_Top Side_1cm_Ch19100_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 10.00	Band 2	LTE-FDD, -	1900.000, 19100	7.97	1.40	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1950-2025-02-21	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

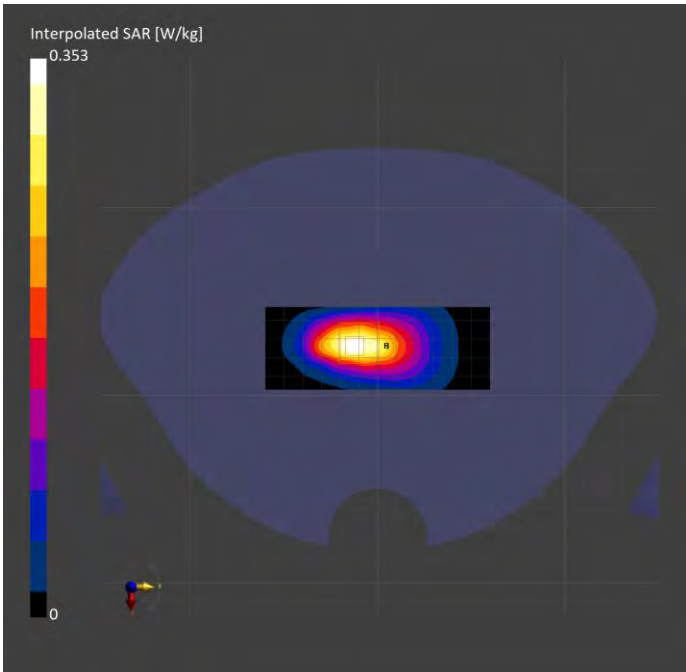
	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-21	2025-02-21
psSAR1g [W/kg]	0.212	0.227
psSAR10g [W/kg]	0.110	0.116
Power Drift [dB]	0.01	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.9
Dist 3dB Peak [mm]		9.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P65 LTE B4_QPSK20M_Left Side_1cm_Ch20175_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE LEFT, 10.00	Band 4	LTE-FDD, -	1732.500, 20175	8.31	1.33	41.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1750-2025-02-17	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

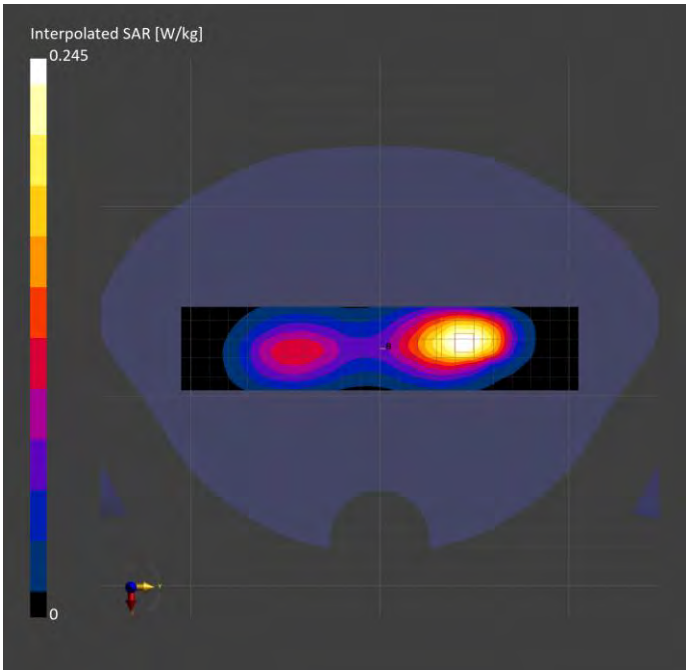
	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-17	2025-02-17
psSAR1g [W/kg]	0.202	0.218
psSAR10g [W/kg]	0.114	0.121
Power Drift [dB]	-0.02	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.2
Dist 3dB Peak [mm]		10.3

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P66 LTE B5_QPSK10M_Left Side_1cm_Ch20450_25RB_OS12

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE LEFT, 10.00	Band 5	LTE-FDD, -	829.000, 20450	9.47	0.939	43.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-02-18	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

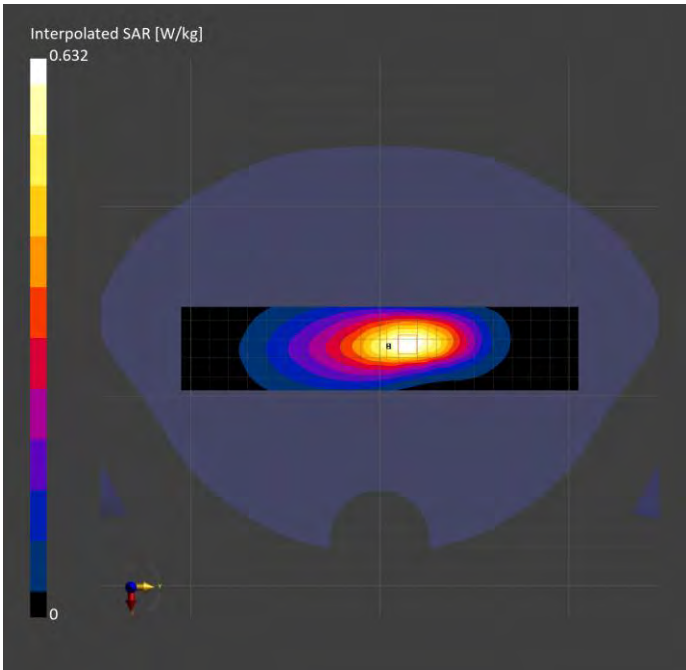
	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-18	2025-02-18
psSAR1g [W/kg]	0.531	0.562
psSAR10g [W/kg]	0.323	0.325
Power Drift [dB]	-0.01	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.1
Dist 3dB Peak [mm]		9.7

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P67 LTE B7_QPSK20M_Bottom Side_1cm_Ch21350_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 7	LTE-FDD, -	2560.000, 21350	7.31	1.91	37.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-02-22	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

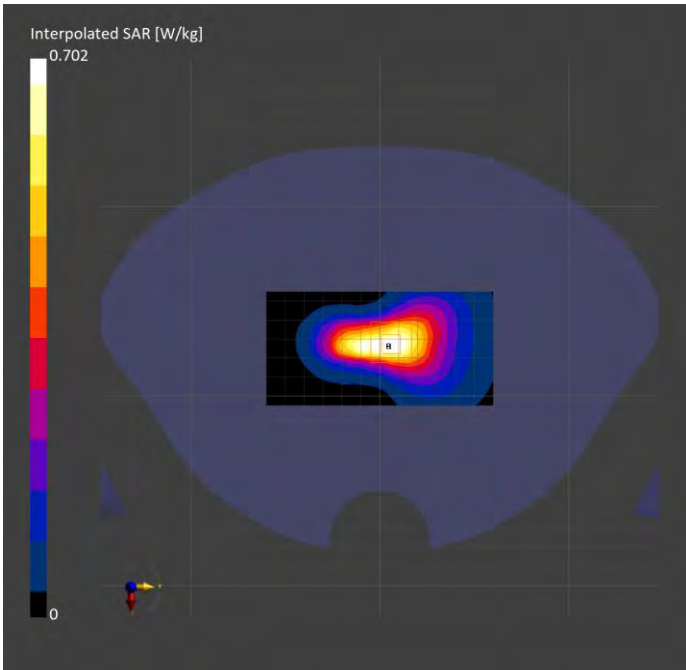
	Area Scan	Zoom Scan
Grid Extents [mm]	60.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-22	2025-02-22
psSAR1g [W/kg]	0.556	0.580
psSAR10g [W/kg]	0.282	0.289
Power Drift [dB]	0.02	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.2
Dist 3dB Peak [mm]		9.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P68 LTE B26_QPSK15M_Rear Face_1cm_Ch26765_1RB_OS37

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 26	LTE-FDD, -	821.500, 26765	9.47	0.915	43.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL835-2025-02-16	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

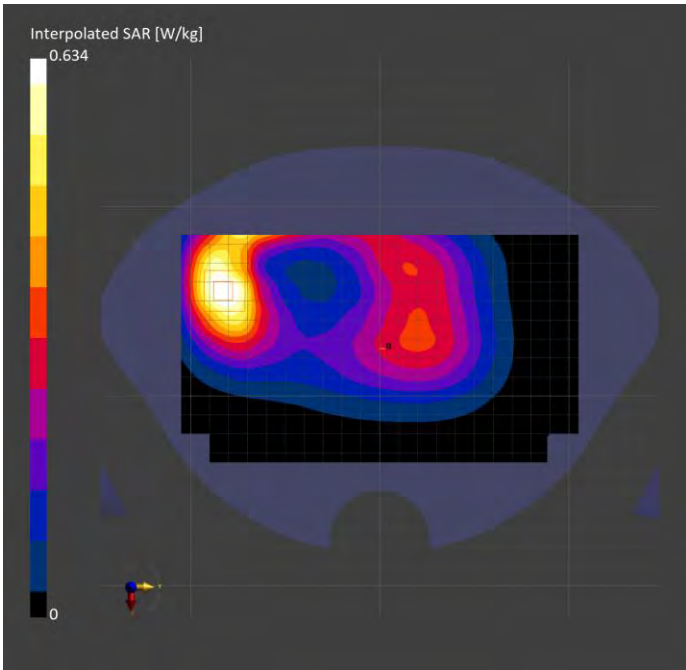
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-16	2025-02-16
psSAR1g [W/kg]	0.556	0.585
psSAR10g [W/kg]	0.365	0.338
Power Drift [dB]	-0.00	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.6
Dist 3dB Peak [mm]		14.7

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P69 LTE B38_QPSK20M_Bottom Side_1cm_Ch38000_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 38	LTE-TDD, -	2595.000, 38000	7.31	1.94	37.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-03-04	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

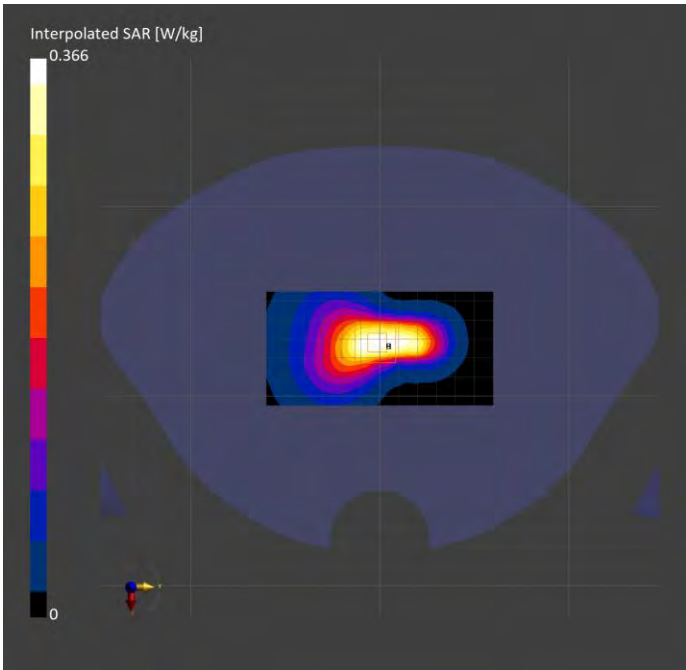
	Area Scan	Zoom Scan
Grid Extents [mm]	60.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-04	2025-03-04
psSAR1g [W/kg]	0.292	0.310
psSAR10g [W/kg]	0.149	0.150
Power Drift [dB]	0.04	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.8
Dist 3dB Peak [mm]		8.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P70 LTE B41_QPSK20M_Bottom Side_1cm_Ch39750_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 41	LTE-TDD, -	2506.000, 39750	7.31	1.88	37.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-02-25	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

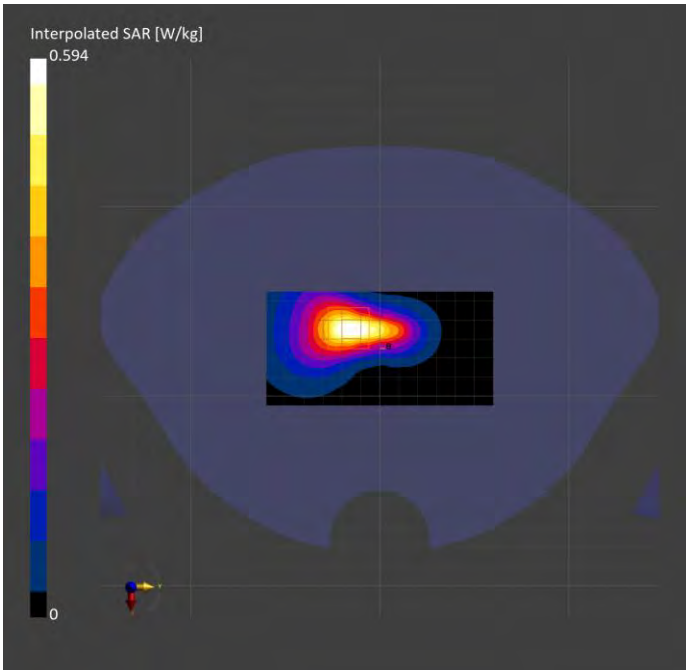
	Area Scan	Zoom Scan
Grid Extents [mm]	60.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-25	2025-02-25
psSAR1g [W/kg]	0.461	0.476
psSAR10g [W/kg]	0.224	0.230
Power Drift [dB]	0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.9
Dist 3dB Peak [mm]		9.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P71 LTE B42_QPSK20M_Rear Face_1cm_Ch43190_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 42	LTE-TDD, -	3560.000, 43190	6.71	2.89	37.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3500-2025-02-23	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

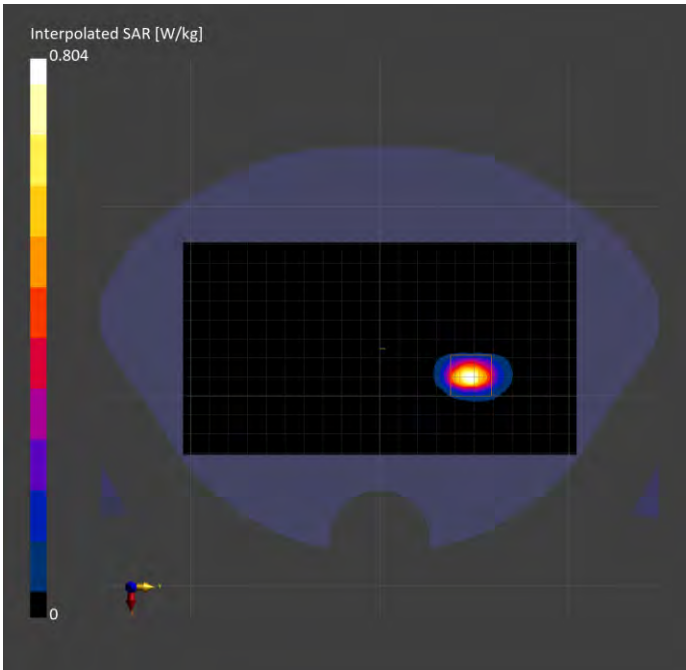
	Area Scan	Zoom Scan
Grid Extents [mm]	112.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-23	2025-02-23
psSAR1g [W/kg]	0.523	0.560
psSAR10g [W/kg]	0.170	0.175
Power Drift [dB]	0.02	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		75.4
Dist 3dB Peak [mm]		6.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P72 LTE B48_QPSK20M_Rear Face_1cm_Ch55340_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 48	LTE-TDD, -	3560.000, 55340	6.71	2.89	37.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3500-2025-02-23	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

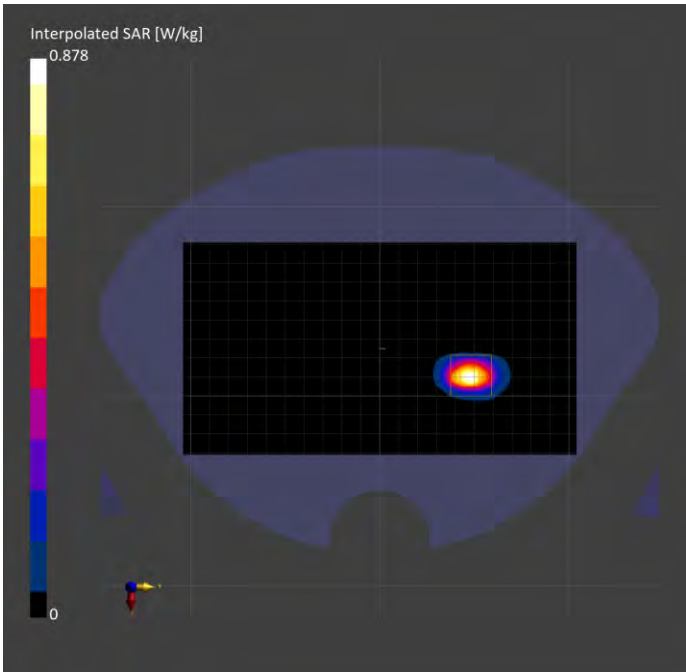
	Area Scan	Zoom Scan
Grid Extents [mm]	112.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-23	2025-02-23
psSAR1g [W/kg]	0.571	0.612
psSAR10g [W/kg]	0.184	0.191
Power Drift [dB]	0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.8
Dist 3dB Peak [mm]		6.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P73 LTE B66_QPSK20M_Bottom Side_1cm_Ch132322_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 66	LTE-FDD, -	1745.000, 132322	8.31	1.40	39.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1750-2025-02-20	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

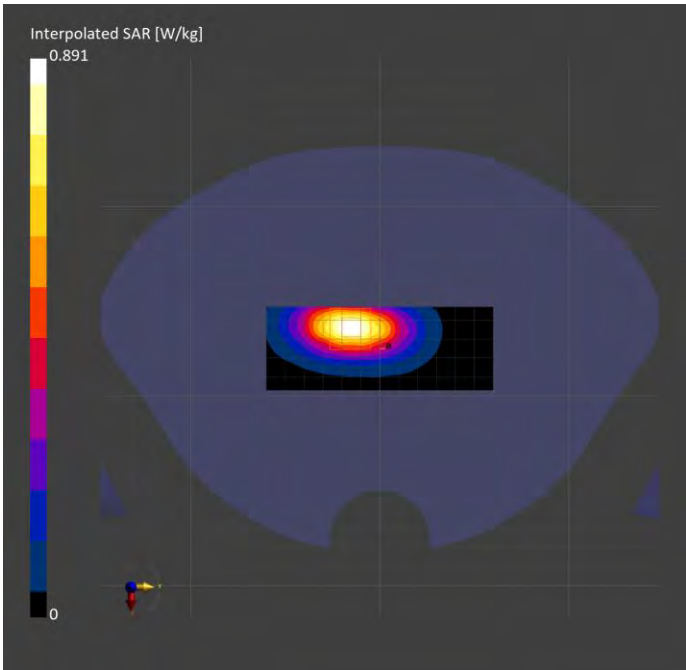
	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-20	2025-02-20
psSAR1g [W/kg]	0.708	0.738
psSAR10g [W/kg]	0.380	0.399
Power Drift [dB]	0.04	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.5
Dist 3dB Peak [mm]		10.3

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P74 FR N2_DFT-QPSK40M_Top Side_1cm_Ch376000_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 10.00	Band n2	5G NR FR1 FDD, -	1880.000, 376000	7.97	1.38	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1950-2025-02-21	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

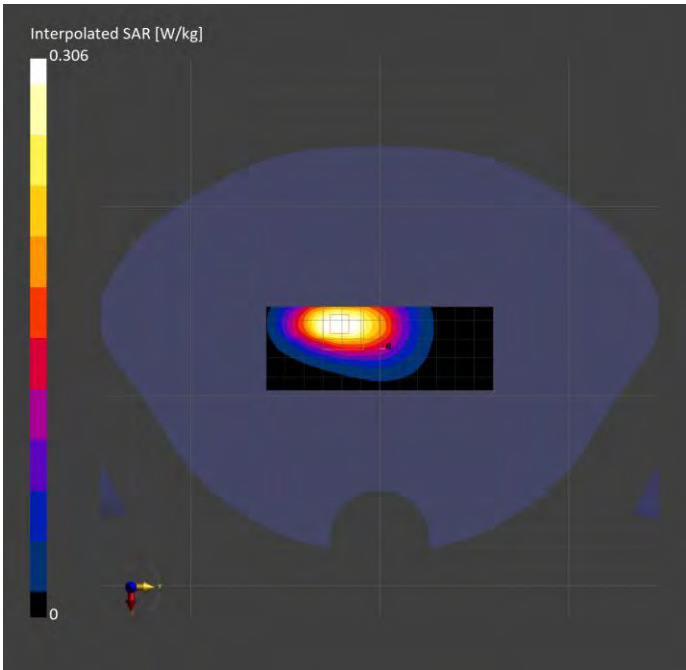
	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-21	2025-02-21
psSAR1g [W/kg]	0.250	0.257
psSAR10g [W/kg]	0.135	0.142
Power Drift [dB]	-0.08	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.0
Dist 3dB Peak [mm]		10.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P75 FR N5_DFT-QPSK25M_Rear Face_1cm_Ch167300_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band n5	5G NR FR1 FDD, -	836.500, 167300	9.47	0.942	43.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL835-2025-02-18	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

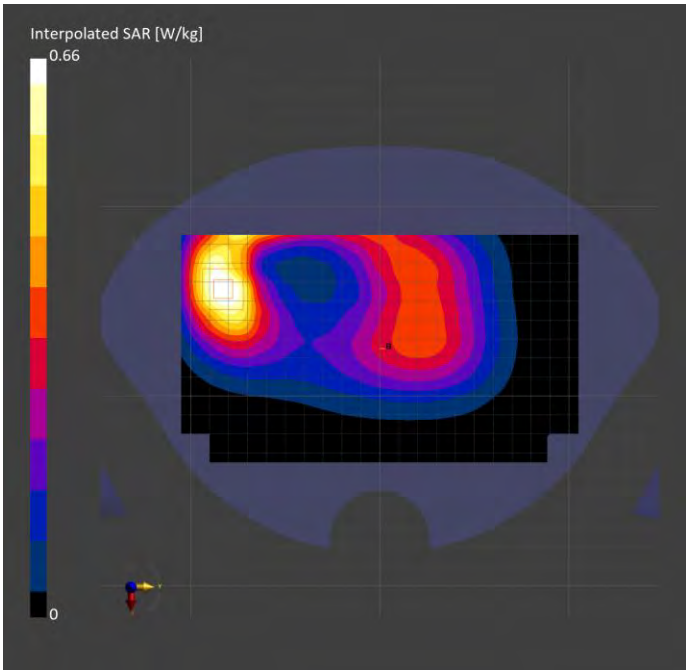
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-18	2025-02-18
psSAR1g [W/kg]	0.579	0.610
psSAR10g [W/kg]	0.379	0.365
Power Drift [dB]	-0.03	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.2
Dist 3dB Peak [mm]		14.7

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P76 FR N7_DFT-QPSK50M_Bottom Side_1cm_Ch507000_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band n7	5G NR FR1 FDD, -	2535.000, 507000	7.31	1.90	37.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-02-22	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

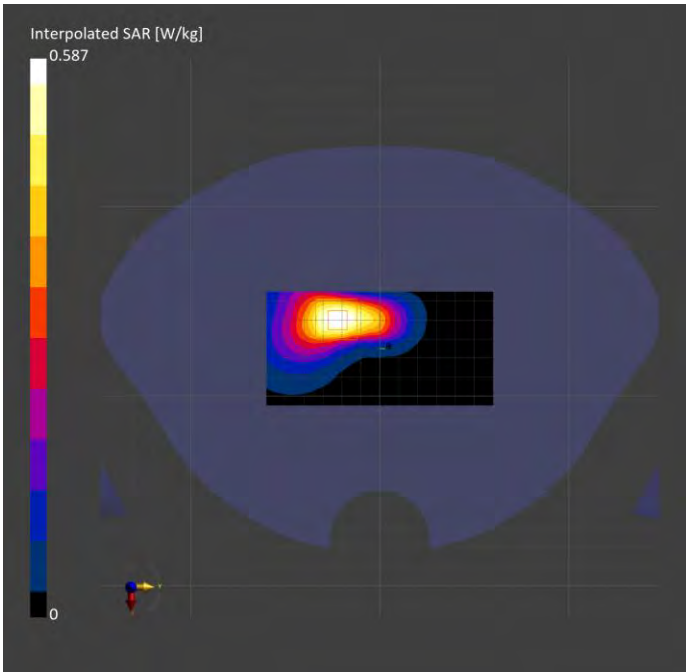
	Area Scan	Zoom Scan
Grid Extents [mm]	60.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-22	2025-02-22
psSAR1g [W/kg]	0.468	0.482
psSAR10g [W/kg]	0.240	0.236
Power Drift [dB]	-0.03	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.7
Dist 3dB Peak [mm]		9.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P77 FR N38_DFT-QPSK40M_Right Side_1cm_Ch519000_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE RIGHT, 10.00	Band n38	5G NR FR1 TDD, -	2595.000, 519000	7.31	1.94	37.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-03-04	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

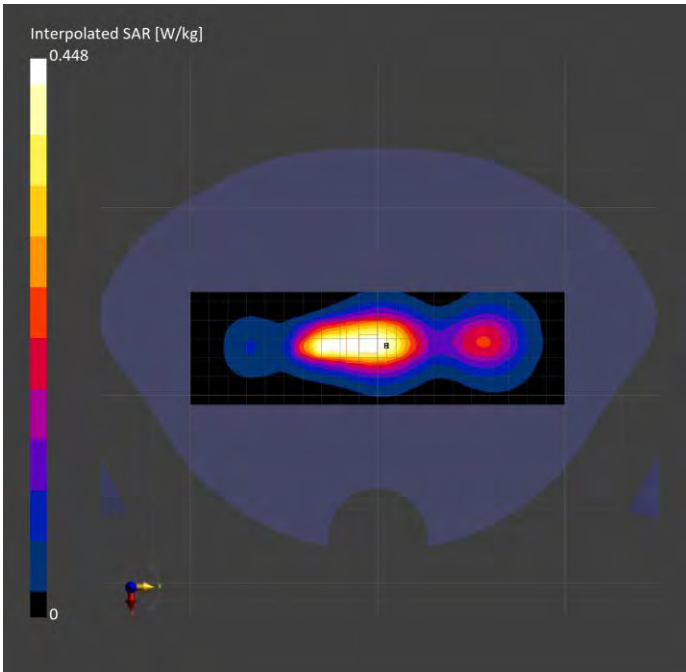
	Area Scan	Zoom Scan
Grid Extents [mm]	60.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-04	2025-03-04
psSAR1g [W/kg]	0.357	0.354
psSAR10g [W/kg]	0.184	0.183
Power Drift [dB]	0.04	-0.13
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.6
Dist 3dB Peak [mm]		9.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P78 FR N41_DFT-QPSK100M_Bottom Side_1cm_Ch509202_135RB_OS69

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band n41	5G NR FR1 TDD, -	2546.010, 509202	7.31	1.90	37.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2550-2025-02-25	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

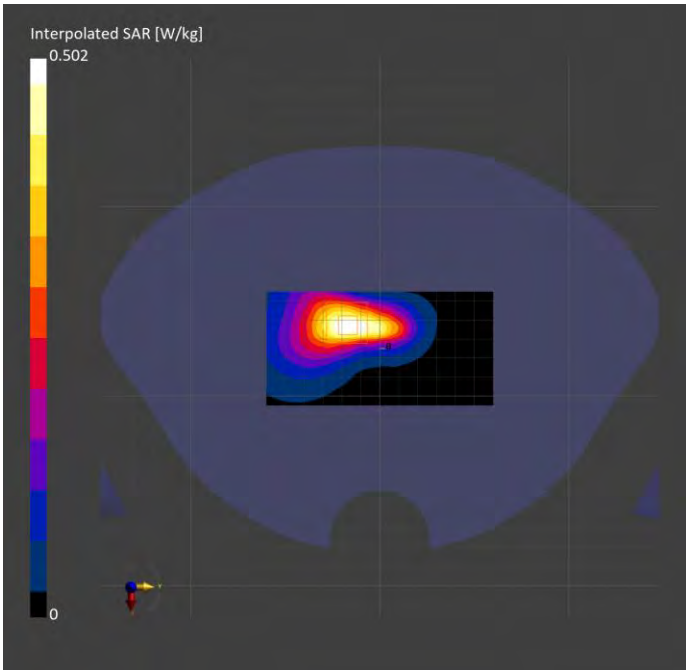
	Area Scan	Zoom Scan
Grid Extents [mm]	60.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-25	2025-02-25
psSAR1g [W/kg]	0.395	0.404
psSAR10g [W/kg]	0.197	0.199
Power Drift [dB]	0.07	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.4
Dist 3dB Peak [mm]		9.9

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P79 FR N48_DFT-QPSK40M_Rear Face_1cm_Ch641666_50RB_OS28

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band n48	5G NR FR1 TDD, -	3624.985, 641666	6.71	2.95	37.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3500-2025-02-23	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

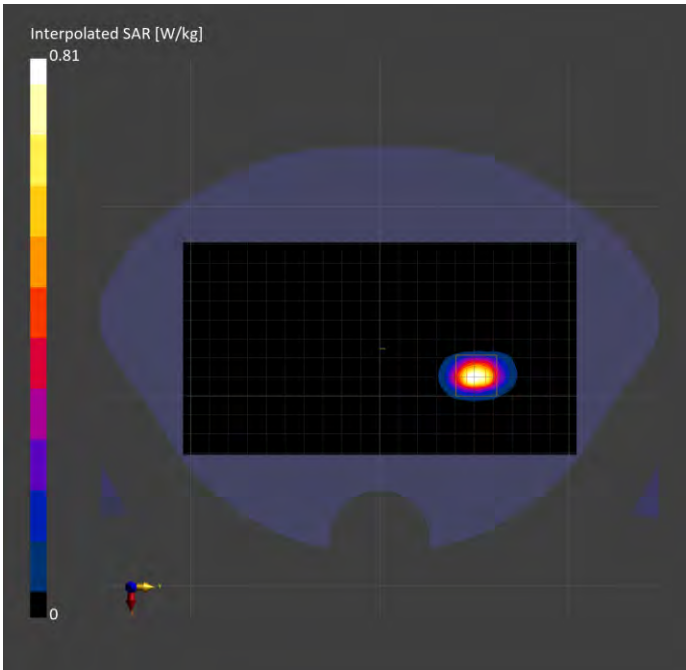
	Area Scan	Zoom Scan
Grid Extents [mm]	112.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-23	2025-02-23
psSAR1g [W/kg]	0.547	0.576
psSAR10g [W/kg]	0.179	0.184
Power Drift [dB]	0.01	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		75.0
Dist 3dB Peak [mm]		6.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P80 FR N66_DFT-QPSK45M_Bottom Side_1cm_Ch351500_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band n66	5G NR FR1 FDD, -	1757.500, 351500	8.31	1.41	39.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1750-2025-02-20	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

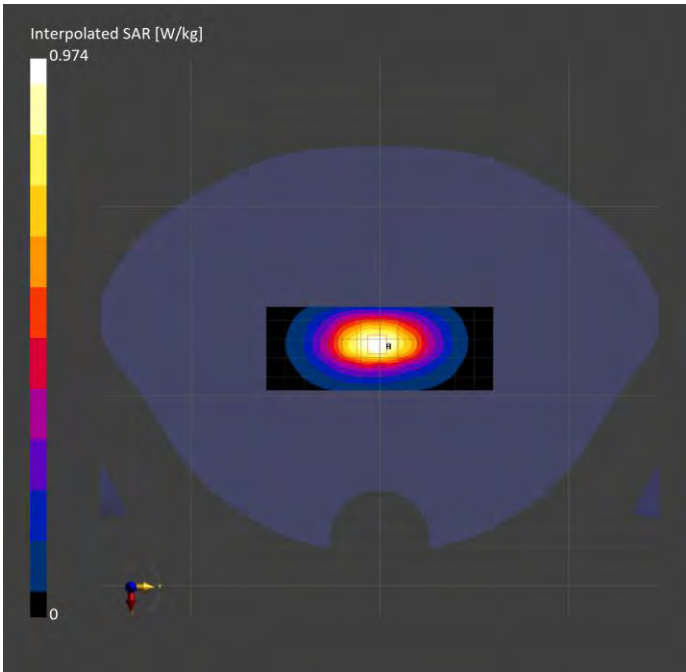
	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-20	2025-02-20
psSAR1g [W/kg]	0.791	0.817
psSAR10g [W/kg]	0.435	0.448
Power Drift [dB]	-0.06	-0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.8
Dist 3dB Peak [mm]		10.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P81 FR N77_DFT-QPSK100M_Rear Face_1cm_Ch656000_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band n77	5G NR FR1 TDD, -	3840.000, 656000	6.4	3.13	36.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3900-2025-03-08	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

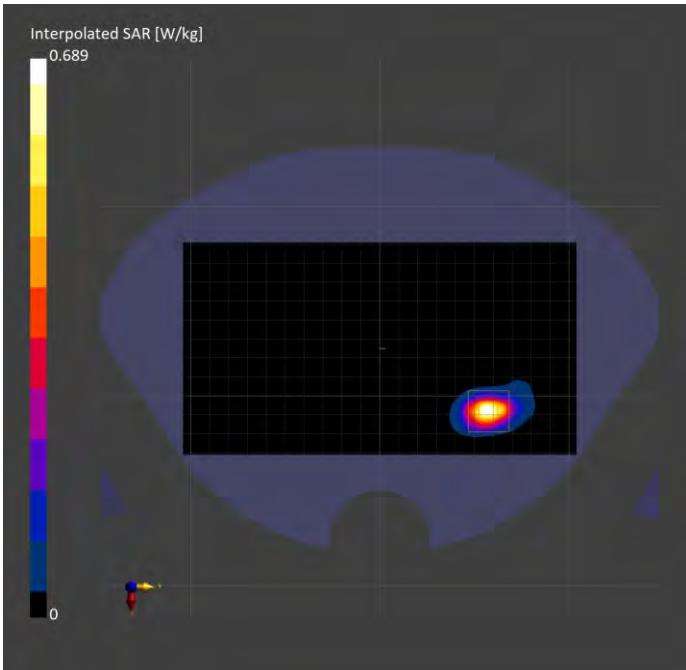
	Area Scan	Zoom Scan
Grid Extents [mm]	112.0 x 208.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	8.0 x 8.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-08	2025-03-08
psSAR1g [W/kg]	0.443	0.456
psSAR10g [W/kg]	0.141	0.143
Power Drift [dB]	-0.05	-0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		74.8
Dist 3dB Peak [mm]		6.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P82 FR N78_DFT-QPSK100M_Top Side_1cm_Ch633334_135RB_OS69

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 10.00	Band n78	5G NR FR1 TDD, -	3500.010, 633334	6.71	2.83	39.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL3500-2025-03-09	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

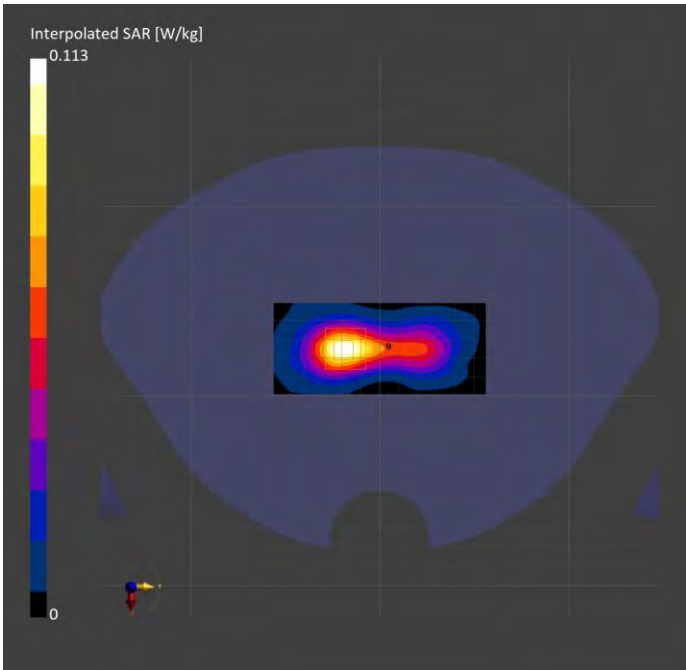
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 112.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	8.0 x 8.0	4.0 x 4.0 x 2.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-09	2025-03-09
psSAR1g [W/kg]	0.082	0.082
psSAR10g [W/kg]	0.035	0.033
Power Drift [dB]	0.07	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		69.0
Dist 3dB Peak [mm]		9.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P83 WLAN2.4G_802.11ax HE20_Right Side_1cm_Ch1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE RIGHT, 10.00	WLAN 2.4GHz	WLAN, -	2412.000, 1	7.46	1.70	40.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL2450-2025-02-27	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

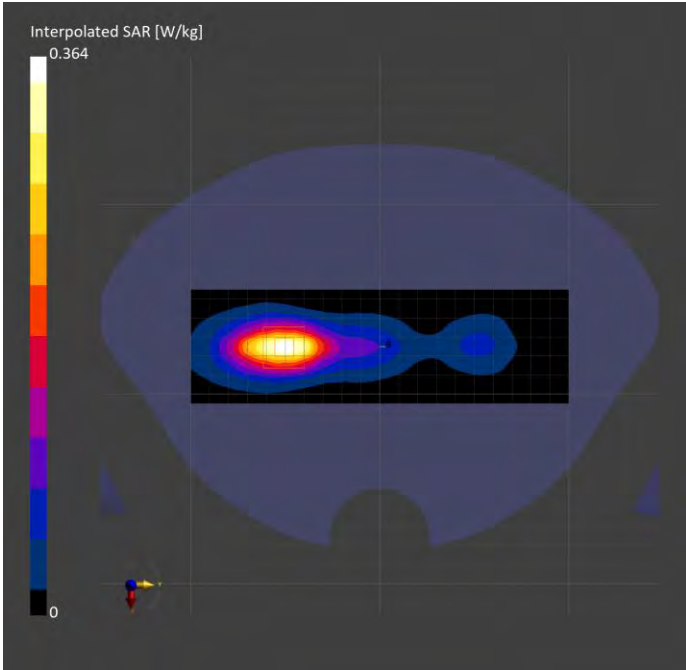
	Area Scan	Zoom Scan
Grid Extents [mm]	60.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 5.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-27	2025-02-27
psSAR1g [W/kg]	0.279	0.229
psSAR10g [W/kg]	0.135	0.137
Power Drift [dB]	-0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		53.1
Dist 3dB Peak [mm]		9.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P84 WLAN5.2G_802.11n HT20_Right Side_1cm_Ch40

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE RIGHT, 10.00	WLAN 5GHz	WLAN, -	5200.000, 40	5.16	4.54	35.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL5G-2025-03-11	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

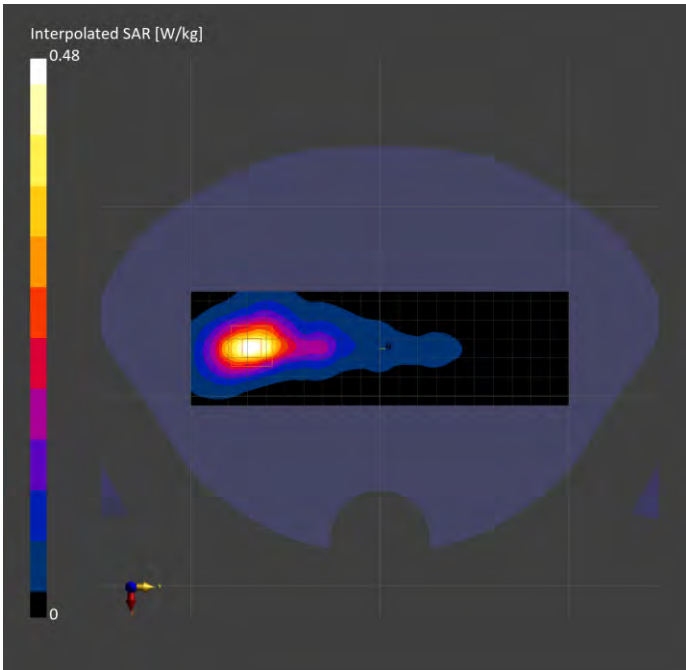
	Area Scan	Zoom Scan
Grid Extents [mm]	60.0 x 200.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 2.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-11	2025-03-11
psSAR1g [W/kg]	0.341	0.309
psSAR10g [W/kg]	0.129	0.125
Power Drift [dB]	-0.02	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		54.7
Dist 3dB Peak [mm]		8.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P85 WLAN5.8G_802.11be HE20_Top Side_1cm_Ch157

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 10.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 10.00	WLAN 5GHz	WLAN, -	5785.000, 157	4.62	5.13	35.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-03-13	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

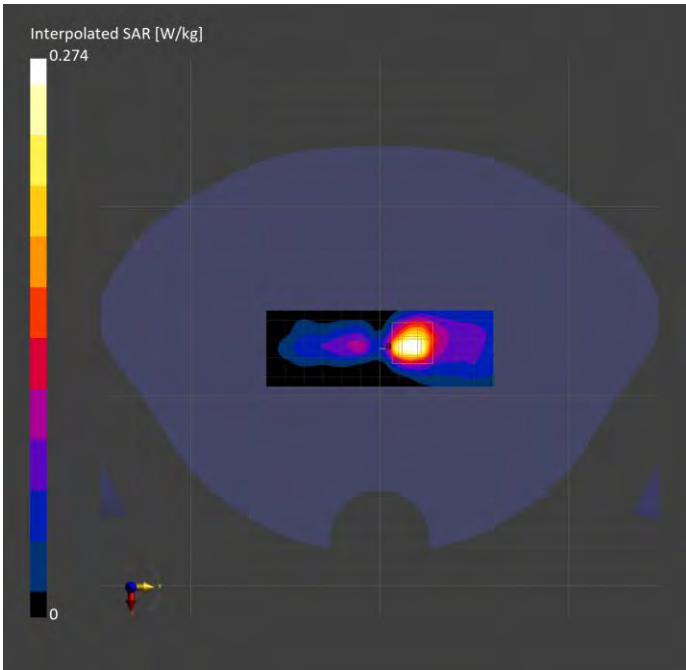
	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 120.0	24.0 x 24.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 2.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-03-13	2025-03-13
psSAR1g [W/kg]	0.203	0.224
psSAR10g [W/kg]	0.068	0.070
Power Drift [dB]	0.38	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		47.8
Dist 3dB Peak [mm]		8.3

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P86 BT_GFSK_Front Face_1cm_Ch0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	FRONT, 10.00	ISM 2.4 GHz Band	Bluetooth, -	2402.000, 0	7.46	1.72	40.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-02-27	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

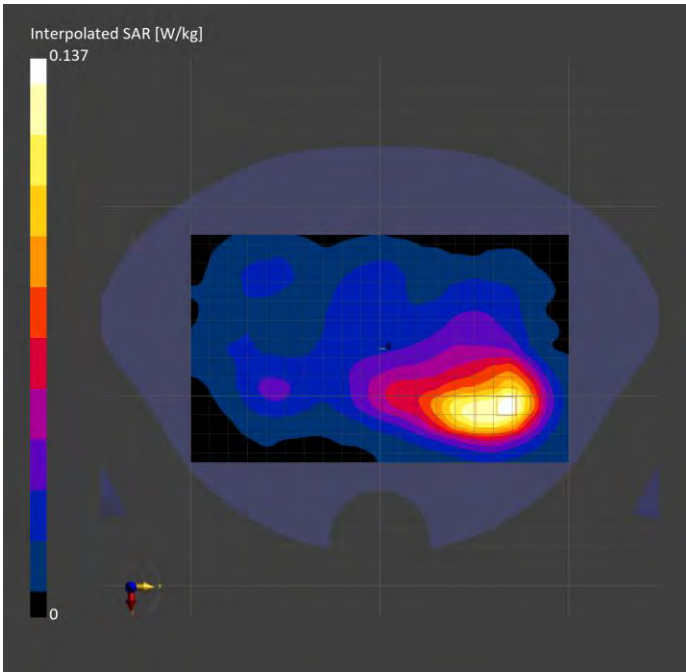
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-27	2025-02-27
psSAR1g [W/kg]	0.107	0.106
psSAR10g [W/kg]	0.059	0.062
Power Drift [dB]	-0.04	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.7
Dist 3dB Peak [mm]		13.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P87 GSM850_GPRS 3Tx Slot_Left Side_0cm_Ch189

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE LEFT, 0.00	GSM 850	GSM, -	836.400, 189	9.47	0.920	43.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL835-2025-02-16	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

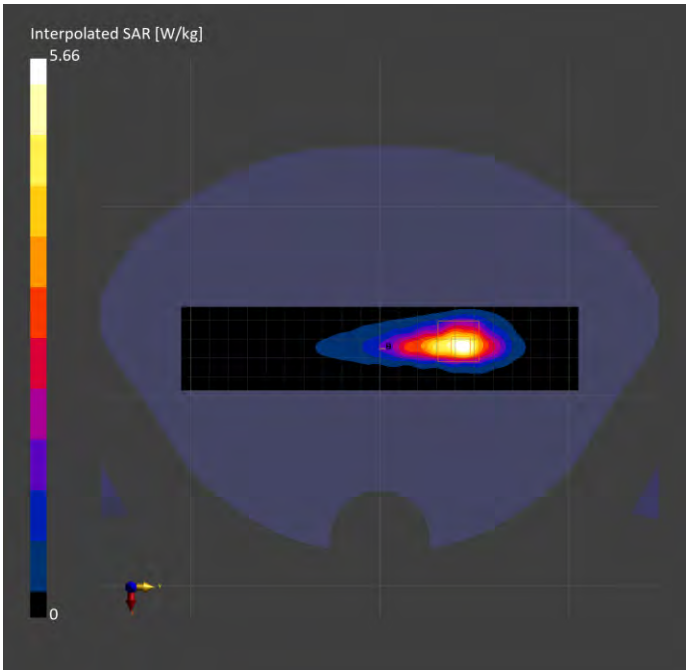
	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 210.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-16	2025-02-16
psSAR1g [W/kg]	4.45	5.43
psSAR10g [W/kg]	2.26	2.09
Power Drift [dB]	-0.00	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		40.0
Dist 3dB Peak [mm]		4.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P88 WCDMA II_RMC12.2K_Top Side_0cm_Ch9262

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 0.00	Band 2	WCDMA, -	1852.400, 9262	7.97	1.36	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1950-2025-02-26	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

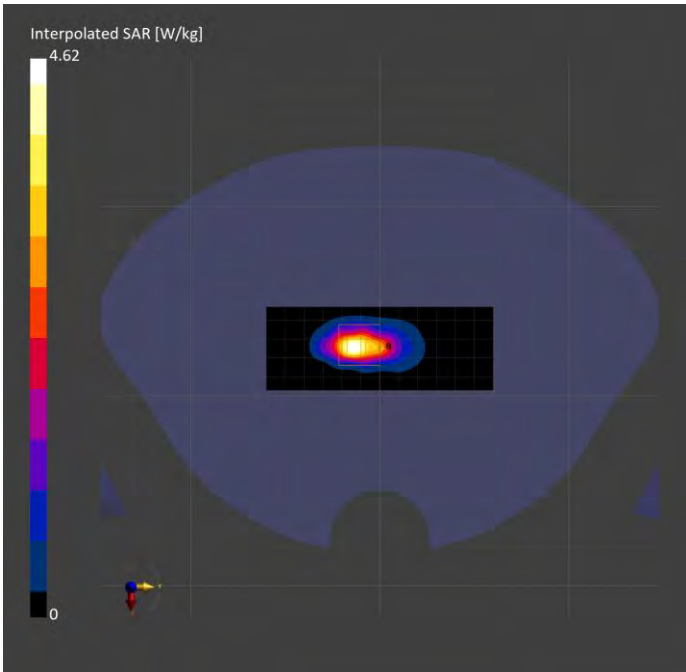
	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-26	2025-02-26
psSAR1g [W/kg]	3.33	3.32
psSAR10g [W/kg]	1.40	1.29
Power Drift [dB]	0.00	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		68.1
Dist 3dB Peak [mm]		4.9

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



P89 WCDMA IV_RMC12.2K_Top Side_0.5cm_Ch1413

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	164.0 x 78.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 0.00	Band 4	WCDMA, -	1732.600, 1413	8.31	1.33	42.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2161	HSL1750-2025-02-17	EX3DV4 - SN3873, 2024-09-29	DAE4 Sn1389, 2024-11-11

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 120.0	32.0 x 32.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	8.0 x 8.0 x 5.0
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-02-17	2025-02-17
psSAR1g [W/kg]	4.23	4.26
psSAR10g [W/kg]	2.28	2.21
Power Drift [dB]	-0.18	-0.16
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		55.0
Dist 3dB Peak [mm]		6.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		

